

1 Intrinsic effect of Mn doping in PZN–12%PT single crystals

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11 In this work we study the influence of manganese doping on the electromechanical properties of
 12 PZN–12%PT single crystal. The full electromechanical tensor of doped PZN–12%PT in the
 13 tetragonal single domain state is determined by the resonance-antiresonance method. Doping leads
 14 to a decrease in the dielectric transverse permittivity ϵ_{11}^T and of the shear piezoelectric coefficient
 15 d_{15} . We show by dielectric constant ϵ_{33}^T measurements that the single domain state in doped crystal
 16 is stable in plates as thin as 90 μm , whereas it was unstable in plates thinner than 300 μm for the
 17 undoped crystals. This intrinsic effect is discussed by using a volume effect model based on the
 18 symmetry conforming principle of point defects. [Ren, Nature Mater. 3, 91 (2004)]. Mn doping
 19 forces the stability of PZN–12%PT single domain state, which makes the doped crystal a most
 20 suitable candidate than the pure crystal for high frequency ultrasonic medical imaging probe.
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22 I. INTRODUCTION

23 High frequency ultrasonic imaging has many clinical ap-
 24 plications because of its improved image resolution.² Its de-
 25 velopment has pushed the limits of ultrasonic imaging tech-
 26 nology, giving diagnostic quality information about
 27 microscopic structures in living tissues. For high frequency
 28 devices, the thickness of the piezoelectric element must be
 29 less than 100 μm (Ref. 3) which has been a technological
 30 challenge for piezoelectric ceramics material. Therefore in
 31 recent years quite a bit of research has been directed to the
 32 development of single crystal piezoelectric materials like
 33 $[(1-x)\text{Pb}(\text{Zn}_{1/3}\text{Nb}_{2/3})\text{O}_3-x\text{PbTiO}_3]$ (PZN–x%PT). In the vi-
 34 cinity of the so-called morphotropic phase boundary (MPB)
 35 at $x=9\%$, PZN–x%PT single crystals poled along a $[001]_C$
 36 direction exhibit ultrahigh piezoelectric coefficients (d_{33}
 37 $=2500$ pC/N) and extremely large electromechanical cou-
 38 pling factor ($k_{33}=92\%$) at room temperature.⁴ Such excellent
 39 properties point to a potential revolution in electromechani-
 40 cal transduction used in ultrasound medical imaging probe.⁵
 41 Currently this application is limited by ferroelectric–
 42 ferroelectric transition present in compositions near the MPB
 43 which increase electromechanical properties temperature de-
 44 pendence, restricting then their temperature usage range. Re-
 45 cently, tetragonal PZN–12%PT single crystals have attracted
 46 more attention because of their high Curie temperature T_C
 47 (~ 190 °C) and no ferroelectric phase transition for $T < T_C$.⁶
 48 Although further away from the MBP, this material possesses
 49 reasonably high electromechanical coupling factor (k_{33}
 50 $=86\%$) and piezoelectric coefficients ($d_{33}=576$ pC/N)
 51 while exhibiting a rather low longitudinal dielectric permit-
 52 tivity ($\epsilon_{33}^T=870$).⁷ With this properties PZN–12%PT is the
 53 best candidate to replace PZT ceramics used in ultrasonic

medical imaging probe. However, for this composition, it
 was demonstrated that the single domain state of samples
 thinner than 300 μm is unstable,^{8,9} while the relevant fre-
 quencies in ultrasonic imaging would require resonating
 plates thinner than 100 μm , making the practical realization
 of resonators a technological challenge.

Doping these compounds with acceptor cation like Mn^{2+}
 has been found to stabilize the domain structure.^{10–13} This
 effect is generally attributed to a gradual pinning of domain
 walls by doping induced defects. These defects migrate to
 the domain boundary and consequently pin the domain walls.
 This effect can therefore be described as an “extrinsic effect”
 since it reduces the contributions to the electromechanical
 properties that are called “extrinsic,” that is resulting from
 domain wall movements.^{10,14} As a result, Mn doping reduces
 longitudinal piezoelectric coefficients (d_{33} and d_{31}) and elec-
 tromechanical coupling factor (k_{33} , k_t , and k_{31}),^{15–17} which
 lessen their capacity to be used in electromechanical trans-
 ducer. Most of the previous studies on materials with multi-
 domain structure attribute the stabilization of domain struc-
 ture and the decrease in piezoelectric constants to the
 extrinsic effect.^{15–17}

The influence of Mn doping on the intrinsic properties of
 the single crystals can be studied by examining the properties
 of doped and undoped crystals in their single domain state.
 Although the existence of a volume effect has been demon-
 strated in single domain BaTiO_3 ,¹³ there are few reports that
 address this question in high performance PZN-PT or
 PMN-PT $[(1-x)\text{PbMg}_{1/3}\text{Nb}_{2/3}\text{O}_3-x\text{PbTiO}_3]$ single crystals.
 A notable exception regarding PZN–12%PT single crystals is
 the work by Zhang *et al.*¹⁸ who studies the influence of dop-
 ing by various cations but does not give the full electromechanical tensor of the crystals.

In this work, we determine the full electromechanical

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TABLE I. Lattice parameters, at room temperature, of doped and nondoped PZN–12% PT single crystals poled along $[001]_C$ direction.

Lattice parameter	a (Å)	c (Å)
Mn–PZN–12%PT	4.019	4.0966
PZN–12%PT	4.025	4.0970

88 tensor of Mn-doped PZN–12%PT single crystals in its single
89 domain state and we study the dependence of domain struc-
90 ture stability with the sample thickness. To explain the ob-
91 tained results we further explored the microscopic origin of
92 Mn doping on the basis of the universal defect symmetry
93 principle.^{1,19–21}

94 II. CRYSTAL GROWTH AND SAMPLE PREPARATION

95 Mn-doped PZN–12%PT single crystals (denoted Mn–
96 PZN–12%PT) were grown using the conventional high-
97 temperature flux method described elsewhere.^{22,23} The con-
98 centration of Mn is of about 1 mol %. At room temperature,
99 x-ray diffraction shows that Mn–PZN–12%PT single crystals
100 have a tetragonal structure with lattice parameters a and c
101 given in Table I. Crystals were oriented along $\langle 001 \rangle_C$
102 pseudocubic directions and cut with different sizes and as-
103 pect ratios according to desired modes of resonance.²⁴ The
104 Mn–PZN–12%PT samples were then polished and gold elec-
105 trodes were sputtered on their relevant faces. Samples are
106 then annealed at 700 K for 2 h to release stress induced by
107 polishing. All samples were poled using the field cooling
108 method²⁵ with a dc poling field of 1 kV/cm applied along a
109 $[001]_C$ direction at 500 K with a cooling rate of 2 K/min. The
110 paraelectric–ferroelectric transition temperature is slightly
111 lower for doped crystals than for undoped crystals (457 K
112 versus 472 K). The electromechanical properties were deter-
113 mined at room temperature by the resonance method²⁴ using
114 an impedance analyzer (Agilent 4294A). The mechanical
115 quality factor was computed using the relation $Q = f_r / (f_1$
116 $- f_2)$, where f_r is the resonance frequency and f_1 and f_2 are
117 the frequencies at 3 dB down to the maximum admittance.

118 III. RESULTS

119 A. Intrinsic effect of Mn doping on the 120 electromechanical properties

121 The full electromechanical tensor of the single domain
122 state 1T contains 11 independent coefficients. Table II shows
123 our results on Mn–PZN–12%PT and those obtained recently
124 on pure PZN–12%PT by Guennou *et al.*²⁶ The comparison
125 shows that the elastic compliances can be considered unaf-
126 fected by doping within the experimental uncertainties. Elec-
127 tromechanical coupling factor, piezoelectric coefficients (d_{33}
128 and d_{31}), and dielectric permittivity (ϵ_{33}^T) show a slight in-
129 crease upon doping. The most pronounced differences be-
130 tween doped and undoped crystals are exhibited by the trans-
131 verse dielectric constant ϵ_{11}^T and the shear piezoelectric
132 coefficient d_{15} : both decrease by approximately 40%. Last,
133 the mechanical quality factors are considerably improved.

TABLE II. Electromechanical properties, at room temperature, of the tetragonal single domain state of Mn-doped and pure PZN–12%PT single crystals.

Properties	Mn–PZN–12%PT	PZN–12%PT ^a
ϵ_{11}^T	6000 ± 1000	10 000 ± 500
ϵ_{33}^T	870 ± 50	750 ± 50
$k_{31}(\%)$	57,9 ± 1,5	54,6 ± 2
k_{33}	88,9 ± 0,4	87,8 ± 1
k_t	60,4 ± 1	60 ± 1
k_{15}	51,6 ± 4	49,7 ± 3
$d_{31}(\text{pm/V})$	–230 ± 8	–207 ± 10
d_{33}	568 ± 30	541 ± 30
d_{15}	400 ± 80	653 ± 100
$s_{11}^E(\text{pm}^2/\text{N})$	20,8 ± 0,5	20,1 ± 1
s_{33}^E	56,9 ± 5	54,5 ± 4
s_{44}^E	18,7 ± 4	19,5 ± 4
s_{66}^E	25,4 ± 27	17,2 ± 19
s_{12}^E	–5,5 ± 11	–4,6 ± 9
s_{13}^E	–17,7 ± 6	–18,2 ± 7
Q_t	233 ± 50	50 ± 20
Q_{31}	880 ± 80	450 ± 100
Q_{33}	600 ± 60	440 ± 100

^aReference 26.

We note that the increase or the decrease due to Mn
doping of a given electromechanical coefficient, ϵ_{ii}^T or $d_{i\alpha}$,
depends on the direction of the ac-electric field. Indeed, all
the piezoelectric and dielectric coefficients that are measured
by application of the low ac-electric field along direction 3
increase slightly. On the other hand coefficients that are mea-
sured by application of electric field along direction 1 or 2
decreases. These results prove that Mn doping have an im-
portant intrinsic effect on the electromechanical properties
that we should take into account.

B. Effect of Mn doping on the stability of single domain state

In pure PZN–12%PT, it has been shown previously that
the tetragonal single domain state 1T was unstable in plates
thinner than 300 μm .⁸ This notably resulted in an increase
in the dielectric constant for thin plates; while the longitudi-
nal dielectric constant ϵ_{33}^T measured on bulk and thick
samples amounts typically to 700, the dielectric constants
measured on thinner plates increased gradually, reaching val-
ues as high as 2000 for 70 μm thick plates. This phenom-
enon, accompanied by a marked decrease in the overall elec-
tromechanical coefficient, is due to the emergence of
domains lying in the plane of the plate.⁸

We carried out the same measurements on the doped
single crystal and measured the dielectric constants for poled
plates of various thicknesses down to 90 μm . Figure 1
shows the normalized longitudinal dielectric constant as a
function of thickness for doped and undoped PZN–12%PT.
For doped single crystal, the dielectric constant remains in-
dependent on the sample thickness at least until 90 μm . This
result shows that Mn doping stabilizes the single domain
state.

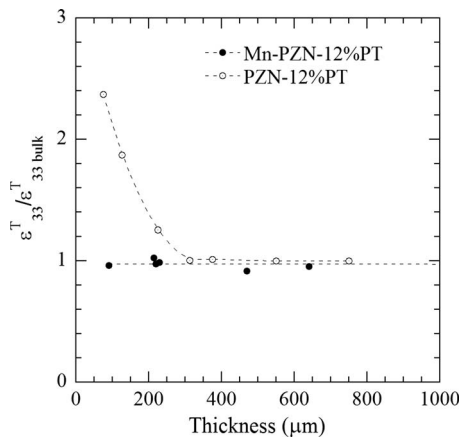


FIG. 1. Normalized longitudinal dielectric constant as a function of plate thickness. The value of ϵ_{33}^T bulk for single domain bulk samples is shown in Table II. Values of nondoped PZN-12%PT are those of Dammak *et al.* (Ref. 8).

166 IV. DISCUSSION

167 Our results show that doping has an influence on the
 168 properties of single domain states, which can only be an
 169 intrinsic effect. It is clear that the “domain walls pinning”
 170 model, described above in the introduction, based on
 171 “boundary effect” cannot explain this Mn doping behavior
 172 because domain walls are not present in the single domain
 173 state. The present experimental results can only be explained
 174 by a volume effect. The volume effect model proposed by
 175 Carl and Härdtl²⁷ and then by Lambeck and Jonker¹³ seems
 176 most relevant. This model is based on a key assumption that
 177 there exist dipolar defects which follow spontaneous polar-
 178 ization P_S orientation after poling with the field cooling
 179 method. However this assumption does not has a micro-
 180 scopic explanation. Recent studies suggest that the volume
 181 effect arises from a symmetry conforming principle of point
 182 defects.^{1,19,20,28} This latter model is widely used to explain
 183 reversible domain switching²¹ and aging behaviors²⁸ in Mn-
 184 doped BaTiO₃ single crystals. In the following, the main
 185 ideas of this model are presented.

186 We first consider the valence and the chemical environ-
 187 ment of Mn ions and their role in the crystal. It was shown in
 188 the case of Mn-PZN-4.5%PT (Refs. 16 and 29) that the
 189 largest fraction of Mn ions is Mn²⁺ ion (>90%) which re-
 190 places mostly titanium. The properties of the single crystal
 191 will thus be largely influenced by the presence of Mn²⁺ ions.
 192 The defect symmetry principle describes a relationship be-
 193 tween crystal symmetry and the “symmetry” of statistical
 194 short-range-order distribution of point defects. To maintain
 195 charge neutrality, O²⁻ vacancies are necessarily produced.
 196 Consequently, the point defects in the crystal are Mn²⁺ dop-
 197 ants and O²⁻ vacancies. When samples are poled using the
 198 field cooling method with a high dc field applied along
 199 [001]_C direction and a low cooling rate (as in our case), O²⁻
 200 vacancies can migrate from O²⁻ site to an other. Within tet-
 201 ragonal structure, the first neighbor O²⁻ sites are not equiva-
 202 lent for the Mn²⁺ dopant. Due to a Coulomb attractive force
 203 between an effectively negative charged dopant and a posi-
 204 tive charged vacancy, the probability of finding an oxygen
 205 vacancy in the nearest neighbor position of the Mn²⁺ dopant

center is predicted to be highest along the crystallographic c 206
 axis. Then, the short-range-order distribution of defects tends 207
 to a tetragonal symmetry, which follows the tetragonal crystal 208
 symmetry.^{19,20} The noncentrosymmetric distribution of 209
 charged defects forms a defect polarization P_D parallel to the 210
 direction of the spontaneous polarization P_S . 211

A key point in this model is the distinction between two 212
 types of dipole moments: ferroelectric dipole moment asso- 213
 ciated to cationic displacement, P_S , and dipole moments re- 214
 lated to oxygen vacancies due to the polar tetragonal defect 215
 symmetry, P_D . This microscopic model agrees well with pre- 216
 vious electron paramagnetic resonance experiments³⁰ and 217
 theoretical modeling^{31,32} which suggest that defect dipoles 218
 tend to align along the spontaneous polarization P_S direction. 219

The stabilization of the single domain state in thin plates 220
 could be explained by the existence of defect dipole mo- 221
 ments which provides forces that block the spontaneous po- 222
 larization in its initial direction (Fig. 1). These forces, in the 223
 so-called “internal field,” are responsible of the shifting of 224
 the polarization-electric field hysteresis loop along the 225
 E-axis.¹³ In addition, these oriented defect dipoles should 226
 relax the structure along c axis and could be on the origin of 227
 the decrease in the measured tetragonal lattice parameter a 228
 perpendicular to the spontaneous polarization (Table I) 229
 which increase the tetragonality, i.e., the c/a ratio. This phe- 230
 nomenon is also observed in iron doped PbTiO₃.³³ 231

On the other hand, it was noticed that a perpendicular 232
 high electric field has to overcome an internal field produced 233
 by P_D before a microscopic dipole moment P_S switching can 234
 happen.²⁸ This makes spontaneous dipole moment switching 235
 in a poled doped single domain sample more difficult com- 236
 pared with the poled undoped sample. If we extrapolate this 237
 result to the low electric fields, we can conclude that the 238
 presence of defect dipole moment P_D makes P_S dipole mo- 239
 ment rotation in a doped single domain sample more difficult 240
 compared with the undoped sample. This phenomena ex- 241
 plains the decrease in dielectric transverse permittivity (ϵ_{11}^T) 242
 and of the shear piezoelectric coefficient (d_{15}) since these 243
 coefficients describe the capacity of polarization rotation un- 244
 der perpendicular low ac-field.^{34,35} 245

V. CONCLUSION

In the present study we have determined the intrinsic 247
 effect of Mn doping on the stability of the single domain 248
 state and the electromechanical properties of tetragonal 249
 PZN-12%PT. Doping induces a decrease in the tetragonal 250
 lattice parameter, a , a stabilization of single domain state, a 251
 decrease in the dielectric transverse permittivity (ϵ_{11}^T) and the 252
 shear piezoelectric coefficient (d_{15}), and a moderate incre- 253
 ment in piezoelectric coefficients (d_{33} and d_{31}) and dielectric 254
 permittivity (ϵ_{33}^T). Using a volume effect model based on the 255
 symmetry conforming principle of point defects leads to the 256
 presence of defect polarization, P_D , which relaxes the struc- 257
 ture along c axis. These defects polarization should thus be 258
 on the origin of the decrease in the lattice parameter, a , and 259
 the reduction in the ability of polarization rotation, leading to 260
 a reduction in the transverse dielectric permittivity and the 261
 shear piezoelectric coefficient, and the stabilization of the 262

263 single domain state down to a thickness of 90 μm . Finally
264 the stability of longitudinal piezoelectric properties with dop-
265 ing represents an important result for applications especially
266 in the high frequency ultrasonic medical imaging probe.

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270 ¹X. Ren, *Nature Mater.* **3**, 91 (2004).
271 ²K. K. Shung and M. J. Zipparo *IEEE Eng. Med. Biol. Mag.* **15**, 20 (1996).
272 ³K. A. Snook, Z. Jian-Zhong, C. H. F. Alves, J. M. Cannata, C. Wo-Hsing,
273 R. J. Meyer, Jr., T. A. Ritter, and K. K. Shung, *IEEE Trans. Ultrason. Ferroelectr. Control* **49**, 169 (2002).
274 ⁴S. E. Park and T. R. Shrout, *J. Appl. Phys.* **82**, 1804 (1997).
275 ⁵K. Uchino, *Piezoelectric Actuators and Ultrasonic Motors*, Kluwer Academic, Boston, 1996).
276 ⁶D. La-Orautapong, B. Noheda, Z.-G. Ye, P. M. Gehring, J. Toulouse, D.
277 E. Cox, and G. Shirane, *Phys. Rev. B* **65**, 144101 (2002).
280 ⁷S. J. Zhang, C. A. Randall, and T. R. Shrout, *Solid State Commun.* **131**, 41
281 (2004).
282 ⁸H. Dammak, M. Guennou, C. Katchazo, M. P. Thi, F. Brochin, T. De-
283 launay, P. Gaucher, E. Le Clézio, and G. Feuillard, Proceedings of the
284 2006 15th IEEE ISAF, 2007, pp. 252–255.
285 ⁹D. Y. Jeong and S. Zhang, *J. Korean Phys. Soc.* **44**, 1527 (2004).
286 ¹⁰D. Damjanovic, *Rep. Prog. Phys.* **61**, 1267 (1998).
287 ¹¹G. Arlt and U. Robels, *Integr. Ferroelectr.* **3**, 343 (1993).
288 ¹²D. A. Hall and M. M. Ben-Omran, *J. Phys.: Condens. Matter* **10**, 9129
289 (1998).
290 ¹³G. H. Lambeck and P. V. Jonker, *J. Phys. Chem. Solids* **47**, 453 (1986).
291 ¹⁴V. S. Postnikov, V. S. Pavlov, and S. K. Turkov, *J. Phys. Chem. Solids* **31**,

1785 (1970). **292**
¹⁵Y. Chen, S. Hirose, D. Viehland, S. Takahashi, and K. Uchino, *Jpn. J. Appl. Phys., Part 1* **39**, 4843 (2000). **293**
¹⁶D. Kobor, L. Lebrun, G. Sebald, and D. Guyomar, *J. Cryst. Growth* **275**, 580 (2005). **294**
¹⁷S. Priya and K. Uchino, *J. Appl. Phys.* **91**, 4515 (2002). **295**
¹⁸S. Zhang, L. Lebrun, C. A. Randall, and T. R. Shrout, *Phys. Status Solidi A* **202**, 151 (2005). **296**
¹⁹X. Ren and K. Otsuka, *Nature (London)* **389**, 579 (1997). **297**
²⁰X. Ren and K. Otsuka, *Phys. Rev. Lett.* **85**, 1016 (2000). **298**
²¹L. X. Zhang, W. Chen, and X. Ren, *Appl. Phys. Lett.* **85**, 5658 (2004). **299**
²²A.-E. Renault, H. Dammak, G. Cabvarin, M. Pham Thi, and P. Gaucher, *Jpn. J. Appl. Phys., Part 1* **41**, 3846 (2002). **300**
²³S. J. Zhang, L. Lebrun, S. Rhee, R. E. Eitel, C. A. Randall, and T. R. Shrout, *J. Cryst. Growth* **210**, 236 (2002). **301**
²⁴IEEE, ANSI/IEEE Standard No. 176–1987. **302**
²⁵A.-E. Renault, H. Dammak, P. Gaucher, M. Pham Thi, and G. Calvarin, Proceedings of the 13th IEEE ISAF, 2002, pp. 439–442. **303**
²⁶M. Guennou, H. Dammak, and M. P. Thi, *J. Appl. Phys.* **104**, 074102 (2008). **304**
²⁷K. Carl and K. H. Härdtl, *Ferroelectrics* **17**, 473 (1978). **305**
²⁸L. Zhang and X. Ren, *Phys. Rev. B* **73**, 094121 (2006). **306**
²⁹D. Kobor, Ph.D. thesis, INSA Lyon (2005). **307**
³⁰W. L. Warren, G. E. Pike, K. Vanheusden, D. Dimos, B. A. Tuttle, and J. Robertson, *J. Appl. Phys.* **79**, 9250 (1996). **308**
³¹U. Robels and G. Arlt, *J. Appl. Phys.* **73**, 3454 (1993). **309**
³²R.-A. Eichel, P. Erhart, P. Traskelin, K. Albe, H. Kungl, and M. J. Hoffmann, *Phys. Rev. Lett.* **100**, 095504 (2008). **310**
³³H. Mestric, R.-A. Eichel, T. Kloss, K.-P. Dinse, So. Laubach, St. Laubach, and P. C. Schmidt, *Phys. Rev. B* **71**, 134109 (2005). **311**
³⁴D. Damjanovic, M. Budimir, M. Davis, and N. Setter, *J. Mater. Sci.* **41**, 65 (2006). **312**
³⁵M. Davis, M. Budimir, D. Damjanovic, and N. Setter, *J. Appl. Phys.* **101**, 054112 (2007). **313**
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